

## Ultrahigh Sensitive Plasmonic Terahertz Detector Based on an Asymmetric Dual-Grating Gate HEMT Structure

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We report on ultrahigh sensitive, broadband terahertz (THz) detectors based on asymmetric double-grating-gate (A-DGG) HEMTs demonstrating a record responsivity of 2.2 kV/W at 1 THz. Hydrodynamic nonlinearities of two-dimensional (2D) plasmons in high-electron-mobility transistors (HEMTs) are promising for fast and sensitive rectification/detection of THz radiation [1], which can be applied to real-time THz imaging/spectroscopic analysis and future THz wireless communications [2]. Recently, InP- and GaN-based HEMTs as well as Si-MOSFETs have demonstrated improved responsivities [3,4], approaching 1 kV/W at 1 THz by introducing narrow-band dipole antenna structure merged with the gate electrode [3].

We propose an A-DGG structure shown in Fig. 1 which can greatly enhance the asymmetry of the cavity boundaries by applying different gate voltages  $V_{g1}$  and  $V_{g2}$  to the two different sub-gratings of the A-DGG. Terahertz electric field distribution and resultant photovoltaic response were numerically simulated using a self-consistent electromagnetic approach combined with the perturbation theory for the hydrodynamic equations for 2D plasmons in HEMTs [5]. Strong build-in asymmetry in the unit cell of the structure can be created by introducing the A-DGG structure. The THz photoresponse dramatically increases if the parts of 2D channel under the fingers of one of the two sub-gratings are depleted. Strong THz photocurrent is generated by the nonlinearity of the plasmon mode resonantly excited in undepleted portions of the 2D electron channel under the unbiased sub-grating of the A-DGG while depleting the channel under the other (biased) sub-grating greatly enhances the channel resistance. Hence, enormous enhancement of the photovoltage is induced between the source and drain contacts of the entire A-DGG-HEMT structure. Figure 2 shows giant enhancement (by four orders of magnitude) of the responsivity in respect to that for a symmetric DGG HEMT.

A-DGG HEMTs have been designed and fabricated using InAlAs/InGaAs/InP material systems (see Fig. 1). Two grating gates G1 and G2 were formed with 65-nm thick Ti/Au/Ti. The geometrical parameters of the A-DGG HEMTs are summarized in Table I. Asymmetric factor, the ratio of the inter-finger spaces,  $d1/d2$ , was fixed to be 0.5. Moreover a chirped grating structure for the G1 finger  $L_{g1}$  was introduced, which can compensate the electron density chirp along the channel under a specific drain-source bias  $V_{ds}$  condition so as to uniform the plasmon frequencies [6].

We conducted room temperature THz photovoltaic measurements with the fabricated detectors using a ring-cavity THz parametric oscillator source delivering tunable monochromatic THz pulsed waves with frequencies from 1 to 3 THz (see Fig. 3) [7]. The responsivity was estimated as  $R_v = \Delta U * S_t / (P_t * S_d)$  where  $\Delta U$  is the THz-radiation induced dc drain voltage,  $P_t$  is the total power of the source on the detector plane,  $S_t$  is the radiation beam spot area, and  $S_d$  is the active area of the detector. Figure 4 shows the measured responsivity of detector #2-4 at 1 THz under zero  $V_{ds}$  condition as a function of gate voltage swing ( $V_{g1,2} - V_{th}$ ); dc voltage of G1:  $V_{g1}$  (G2:  $V_{g2}$ ) is swept while  $V_{g2}$  ( $V_{g1}$ ) is floated (biased at 0 V). The best result with  $R_v = 2.2$  kV/W was obtained when sweeping  $V_{g1}$  to the threshold  $V_{th}$ . It is worth to stress that even at higher frequencies relatively high responsivities are obtained with detectors #2-3 having shorter  $L_{g1}$ . As seen in the inset of Fig. 4, the responsivities monotonically decrease from 1.7 kV/W at 1 THz to 0.52 kV/W at 2 THz. All these values are, to the authors' knowledge, the best ever reported at these frequencies. Figure 5 demonstrates excellent noise equivalent power (NEP) for detectors (a) #2-4 and (b) #2-3 as a function of  $V_{g1,2}$ . The detector #2-3 exhibits extremely low NEP with the minimal value 15 pW/Hz<sup>0.5</sup> at 1 THz. These values are lower than those of commercial room temperature THz detectors such as Golay cells (200–400 pW/Hz<sup>0.5</sup>) or SBDs (100 pW/Hz<sup>0.5</sup>) [4].

In conclusion, InP-based A-DGG HEMTs demonstrate a record responsivity of 2.2 kV/W at 1 THz with a superior low NEP of 15 pW/Hz<sup>0.5</sup>. These results give a major breakthrough towards the achievement of ultrahigh sensitive THz detectors for room temperature operation.

## References

- [1] M. Dyakonov, and M. Shur, "Detection, mixing, and frequency multiplication of terahertz radiation by two-dimensional electronic fluid," IEEE Trans. Electron. Dev., Vol. 43, pp. 1640–1645, 1996.
- [2] M. Tonouchi, "Cutting-edge terahertz technology," Nature Photon., Vol. 14, pp. 97–105, 2007.
- [3] T. Tanigawa, T. Onishi, S. Takigawa and T. Otsuji, "Enhanced responsivity in a novel AlGaIn/GaN plasmon-resonant terahertz detector using gate-dipole antenna with parasitic elements," 68th Device Research Conf. Dig., (Notre Dame, IN, June 2010) pp. 167–168.
- [4] F. Schuster, D. Coquillat, H. Videler, M. Sakowicz, F. Teppe, L. Dussot, B. Giffard, T. Skotnicki, and W. Knap, "Broadband terahertz imaging with highly sensitive silicon CMOS detectors," Opt. Express, Vol. 19, pp. 7827–7832, 2011.
- [5] G.M. Aizin, D.V. Fateev, G.M. Tsymbalov, and V.V. Popov, "Terahertz plasmon photoresponse in a density modulated two-dimensional electron channel of a GaAs/AlGaAs field-effect transistor," Appl. Phys. Lett., Vol. 91, iss. 163507, 2007.
- [6] T. Nishimura, N. Magome, H.-C. Kang, T. Otsuji, "Spectral narrowing effect of a novel super-grating dual-gate structure for plasmon-resonant terahertz emitter," IEICE Trans. Electron., Vol. E92-C, pp. 696–702, 2009.
- [7] H. Minamide, T. Ikari and H. Ito, "Frequency-agile terahertz-wave parametric oscillator in a ring-cavity configuration," Rev. Sci. Instrum., Vol. 80, iss. 123104, 2009.

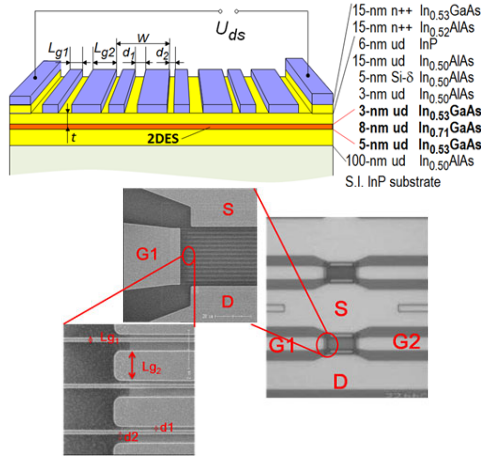


Fig. 1. Schematic view and SEM images of an asymmetric double-grating-gate (A-DGG) HEMT THz detector.  $L_{g1} = 200$  nm,  $L_{g2} = 400$  nm,  $d_1 = 200$  nm,  $d_2 = 400$  nm.

Table I. Design parameters.

Sample #	2-3	2-4
$L_{g1}$ (nm)	215~430	400~705
$d_1/d_2$ (nm)	200/400	400/800
$L_{g2}$ (nm)	1600	1600
# of fingers: G1/G2	8/9	6/7
Active area ( $\mu\text{m}^2$ )	20 x 20	20 x 20

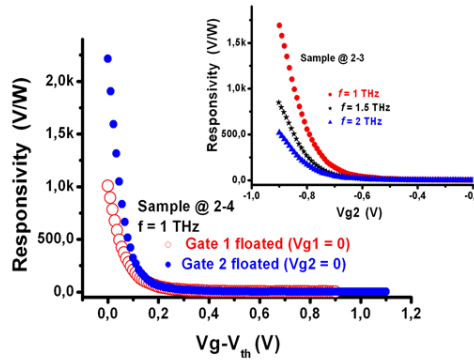


Fig. 4. Responsivity of detector #2-4 as a function of gate voltage swing ( $V_{g1}-V_{th}$  or  $V_{g2}-V_{th}$ ) at 1 THz. The inset: responsivities of detector #2-3 at 1, 1.5, and 2 THz as functions of  $V_{g2}$  when G1 is floated.

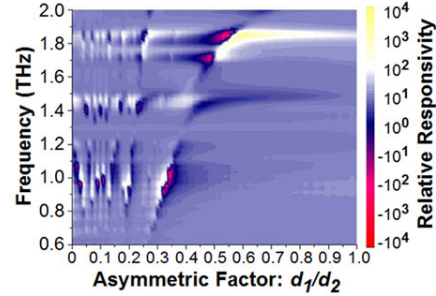


Fig. 3. Simulated relative responsivity for an A-DGG HEMT.  $L_{g1} = 400$  nm,  $L_{g2} = 2.4$   $\mu\text{m}$ ,  $d_1 + d_2 = 800$  nm,  $W = 3.6$   $\mu\text{m}$ . Electron density under the gate G1 and G2 are  $2.5 \times 10^{12}$  and  $2.5 \times 10^{12}$   $\text{cm}^{-2}$ , respectively.

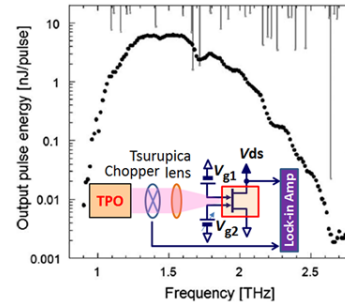


Fig. 4. Experimental setup and output profile of the tunable THz parametric oscillator (TPO) used as the light source.

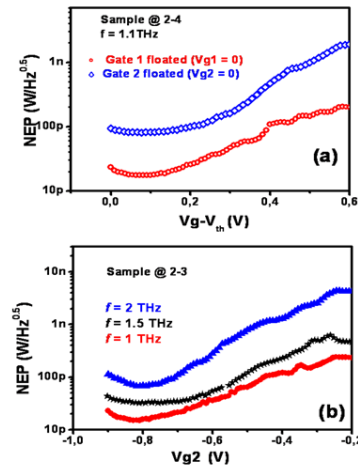


Fig. 5. Measured noise equivalent power for (a) sample #2-4 at 1 THz as functions of the gate voltage swings  $V_{g1}-V_{th}$  and  $V_{g2}-V_{th}$  and (b) sample #2-3 at 1, 1.5, and 2 THz as a function of the gate voltage swing  $V_{g2}-V_{th}$ .